

INSTRUMENT FACILITIES AVAILABLE AT THE INDIVIDUAL SAIFs

EPMA Facility, Indian Institute of Technology, Roorkee

Sl. No.	Instrument	Make/ Model	Major Specifications/ Accessories available	Type of measurement/analysis available
1.	Electron Probe Micro Analyser	JEOL, JXA 8600 M Super Probe	3-Channel wavelength dispersive spectrometer for analyzing elements; Acc. voltage: 0.5 to 50 kV; Probe diameter: 0 to 300 μm ; Objective Aperture: 70, 130, 170 & 240 μm ; B.S. detection, X-ray mapping accessories and software for analysis	Qualitative and quantitative analysis including trace element concentration analysis; Detectable elements B ⁵ to U ⁹² ; 3D map analysis; Chemical shift analysis; Spectrum deconvolution; Area map analysis.